

Specification for Approval

Date: 2021/08/16

Customer : 天诚科技

TAI-TECH P/N: SWI0603F-SERIES

CUSTOMER P/N:

DESCRIPTION:

QUANTITY:

REMARK:	
Customer Approval Feedback	

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TAI-TECH Advanced Electronics Co., Ltd

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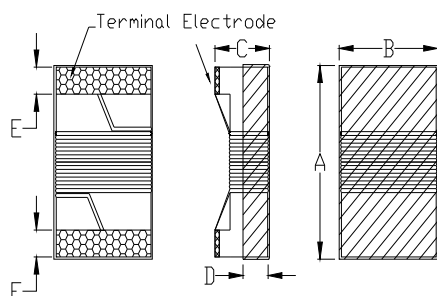
High Frequency Winding Type Chip Inductor SWI0603F-SERIES

1. Features

- 1.Ceramic core wire wound construction.
- 2.No batch to batch variations in inductance
- 3.High Reliability due to ceramic wire wound construction.
- 4.High frequency application.
- 5.Small footprint as well as low profile.
- 6.100% Lead(Pb) & Halogen-Free and RoHS compliant.



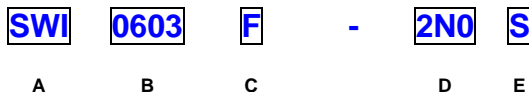
2. Dimensions



Size	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)
SWI0603	1.80 max.	1.20 max.	1.20 max.	0.38 ref.	0.35±0.1

Unit:mm

3. Part Numbering

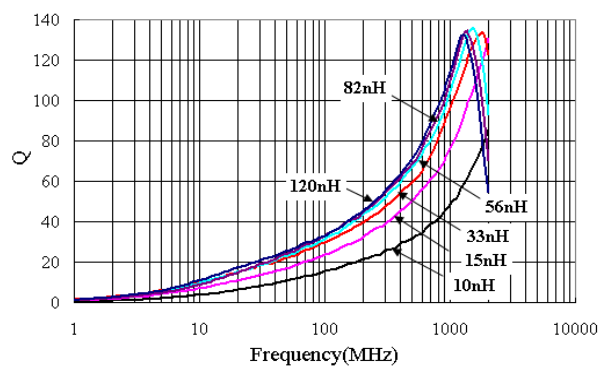
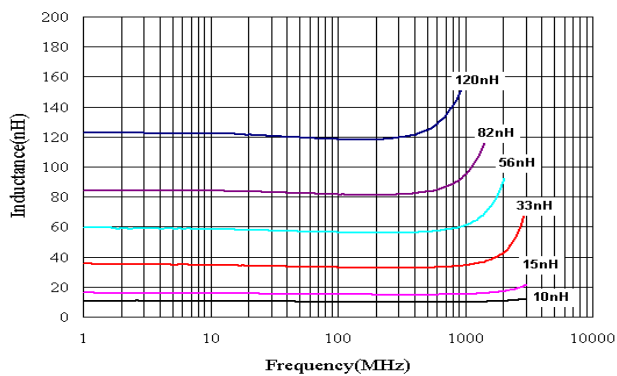


- A: Series
 B: Dimension LxW
 C: Lead free type
 D: Inductance 2N0=2.0nH
 E: Inductance Tolerance C=±0.2nH , S=±0.3nH , J=±5% , K=±10%

4. Specification

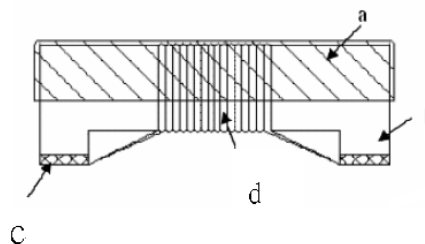
Part Number	Inductance (nH)	Tolerance	Test Frequency (Hz)	Q @ 250MHz min.	Rated Current (mA) max.	DCR (Ω) max.	SRF (MHz) min.
SWI0603F-2N0□	2.0	C,S	0.1V/250M	13	700	0.07	8000
SWI0603F-3N9□	3.9	C,S	0.1V/250M	22	700	0.07	6900
SWI0603F-4N7□	4.7	C,J,K	0.1V/250M	20	700	0.12	5800
SWI0603F-6N8□	6.8	C,J,K	0.1V/250M	27	700	0.08	5800
SWI0603F-8N2□	8.2	C,J,K	0.1V/250M	30	700	0.13	4200
SWI0603F-10N□	10	J,K	0.1V/250M	31	700	0.13	4800
SWI0603F-12N□	12	J,K	0.1V/250M	35	700	0.13	4000
SWI0603F-15N□	15	J,K	0.1V/250M	35	700	0.13	4000
SWI0603F-18N□	18	J,K	0.1V/250M	35	700	0.16	3100

Part Number	Inductance (nH)	Tolerance	Test Frequency (Hz)	Q @ 250MHz min.	Rated Current (mA) max.	DCR (Ω) max.	SRF (MHz) min.
SWI0603F-22N□	22	J,K	0.1V/250M	38	700	0.23	3000
SWI0603F-24N□	24	J,K	0.1V/250M	38	700	0.13	2800
SWI0603F-27N□	27	J,K	0.1V/250M	40	600	0.14	2800
SWI0603F-33N□	33	J,K	0.1V/250M	40	600	0.22	2300
SWI0603F-39N□	39	J,K	0.1V/250M	40	600	0.30	2200
SWI0603F-47N□	47	J,K	0.1V/200M	38	600	0.35	2000
SWI0603F-56N□	56	J,K	0.1V/200M	38	600	0.37	1900
SWI0603F-68N□	68	J,K	0.1V/200M	37	600	0.43	1700
SWI0603F-72N□	72	J,K	0.1V/150M	34	400	0.42	1700
SWI0603F-82N□	82	J,K	0.1V/150M	34	400	0.71	1700
SWI0603F-R10□	100	J,K	0.1V/150M	34	400	0.78	1400
SWI0603F-R12□	120	J,K	0.1V/150M	32	300	0.84	1300
SWI0603F-R15□	150	J,K	0.1V/150M	28	280	0.96	990
SWI0603F-R18□	180	J,K	0.1V/100M	25	240	1.52	990
SWI0603F-R22□	220	J,K	0.1V/100M	25	200	2.02	900
SWI0603F-R27□	270	J,K	0.1V/100M	24	170	2.36	900
SWI0603F-R33□	330	J,K	0.1V/100M	24	185	3.40	700
SWI0603F-R39□	390	J,K	0.1V/100M	24	100	3.60	900



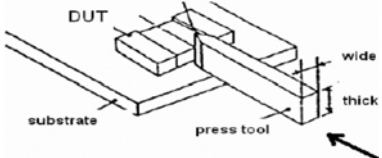
5. Materials

No.	Description	Specification
a.	Upper Plate	UV Glue
b.	Core	Ceramics Core
c.	Termination	Tin Pb Free
d.	Wire	Enameled Copper Wire



6. Reliability and Test Condition

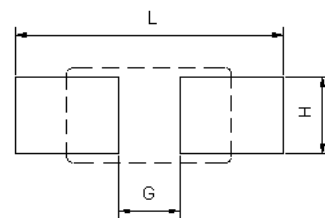
Item	Performance	Test Condition
Operating temperature	-40~+125°C (Including self - temperature rise)	
Storage temperature	-40~+125°C (on board)	
Electrical Performance Test		
Inductance L	Refer to standard electrical characteristic list	Agilent-4291, Agilent-4287
Q		Agilent-4192, Agilent-4285
SRF		Agilent-4291 Agilent-4192
DC Resistance		Agilent-34420A
Rated Current		Applied the current to coils, the inductance change shall be less than 20% to initial value.
Reliability Test		
Life Test	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DCclassification Reflow Profiles) Temperature : 125±2°C Applied current : rated current Duration : 1000±12hrs Measured at room temperature after placing for 24±2 hrs
Load Humidity		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DCclassification Reflow Profiles) Humidity : 85±2%R.H, Temperature : 85°C±2°C Duration : 1000hrs Min. with 100% rated current Measured at room temperature after placing for 24±2 hrs
Moisture Resistance		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DCclassification Reflow Profiles) 1. Baked at 50°C for 25hrs, measured at room temperature after placing for 4 hrs. 2. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs. 3. Raise temperature to 65±2°C 90-100%RH in 2.5hrs, and keep 3 hours, cool down to 25°C in 2.5hrs,keep at 25°C for 2 hrs then keep at -10°C for 3 hrs 4. Keep at 25°C 80-100%RH for 15min and vibrate at the frequency of 10 to 55 Hz to 10 Hz, measure at room temperature after placing for 1~2 hrs.
Thermal shock		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DCclassification Reflow Profiles) Condition for 1 cycle Step1 : -40±2°C 30±5min Step2 : 25±2°C ≤ 0.5min Step3 : 125±2°C 30±5min Number of cycles : 500 Measured at room temperature after placing for 24±2 hrs
Vibration		Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes Equipment : Vibration checker Total Amplitude:1.52mm±10% Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations).

Item	Performance	Test Condition															
Shock	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	<table border="1"> <thead> <tr> <th>Type</th> <th>Peak value (g's)</th> <th>Normal duration (D) (ms)</th> <th>Wave form</th> <th>Velocity change (Vi)ft/sec</th> </tr> </thead> <tbody> <tr> <td>SMD</td> <td>1500</td> <td>0.5</td> <td>Half-sine</td> <td>15.4</td> </tr> <tr> <td>Lead</td> <td>100</td> <td>6</td> <td>Half-sine</td> <td>12.3</td> </tr> </tbody> </table>	Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec	SMD	1500	0.5	Half-sine	15.4	Lead	100	6	Half-sine	12.3
Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec													
SMD	1500	0.5	Half-sine	15.4													
Lead	100	6	Half-sine	12.3													
Bending		Shall be mounted on a FR4 substrate of the following dimensions: >=0805:40x100x1.2mm <0805:40x100x0.8mm Bending depth: >=0805:1.2mm <0805:0.8mm duration of 10 sec.															
Soderability	More than 95% of the terminal electrode should be covered with solder.	Preheat: 150°C,60sec. Solder: Sn96.5% Ag3% Cu0.5% Temperature: 245±5°C. Flux for lead free: Rosin. 9.5%. Dip time: 4±1sec. Depth: completely cover the termination															
Resistance to Soldering Heat	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Number of heat cycles: 1 <table border="1"> <thead> <tr> <th>Temperature (°C)</th> <th>Time(s)</th> <th>Temperature ramp/immersion and emersion rate</th> </tr> </thead> <tbody> <tr> <td>260 ±5(solder temp)</td> <td>10 ±1</td> <td>25mm/s ±6 mm/s</td> </tr> </tbody> </table>	Temperature (°C)	Time(s)	Temperature ramp/immersion and emersion rate	260 ±5(solder temp)	10 ±1	25mm/s ±6 mm/s									
Temperature (°C)	Time(s)	Temperature ramp/immersion and emersion rate															
260 ±5(solder temp)	10 ±1	25mm/s ±6 mm/s															
Terminal Strength		Preconditioning: Run through IR reflow for 2 times.(IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force (>0805:1kg , <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested. 															

7. Soldering and Mounting

7-1. Recommended PC Board Pattern

Chip size						Land Patterns For Reflow Soldering			
Series	Type	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)	L(mm)	G(mm)	H(mm)
SWI	0603	1.80max.	1.20max.	1.20max.	0.38 ref	0.35±0.1	1.92	0.90	1.02



PC board should be designed so that products can prevent damage from mechanical stress when warping the board. Products shall be positioned in the sideways direction to against the mechanical stress to prevent failure.

7-2. Soldering

Mildly activated rosin fluxes are preferred. TAI-TECH terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

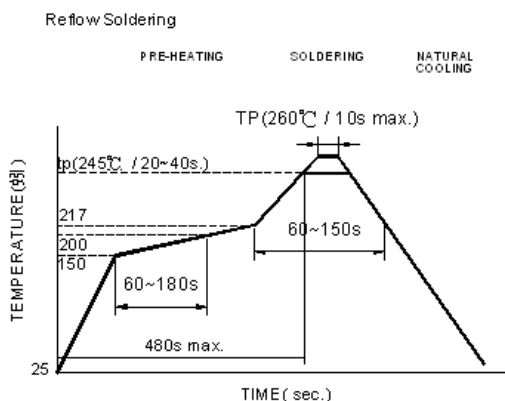
7-2.1 Solder re-flow:

Recommended temperature profiles for re-flow soldering in Figure 1.

7-2.2 Soldering Iron(Figure 2):

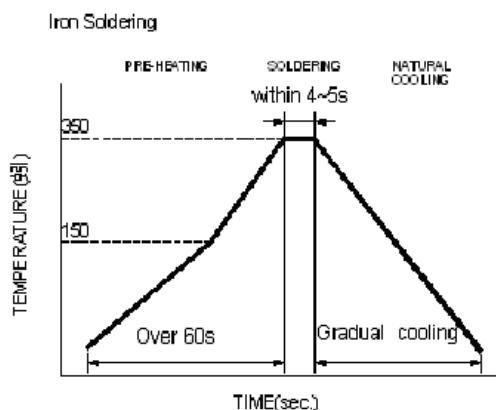
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Note :
- Preheat circuit and products to 150°C
 - Never contact the ceramic with the iron tip
 - Use a 20 watt soldering iron with tip diameter of 1.0mm
 - 280°C tip temperature (max)
 - 1.0mm tip diameter (max)
 - Limit soldering time to 3 sec.



Reflow times: 3 times max.

Fig.1

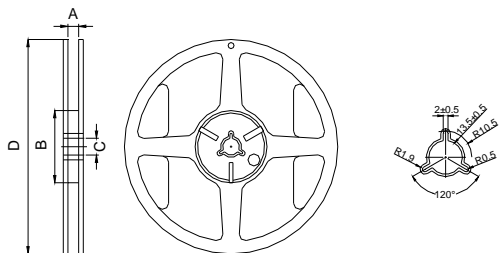


Iron Soldering times: 1 times max.

Fig.2

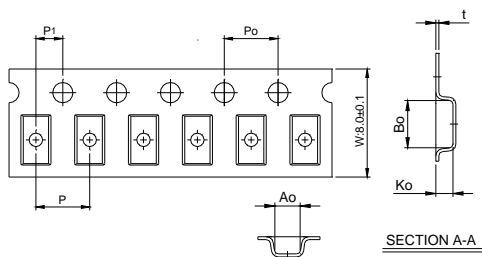
8. Packaging Information

8-1. Reel Dimension



Type	A(mm)	B(mm)	C(mm)	D(mm)
7"x8mm	8.4±0.5	60±2	13.5±0.5	178±2

8-2.1 Tape Dimension / 8mm(black anti-static electricity carrier tape)

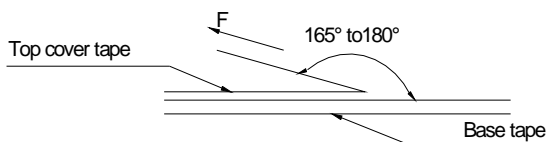


Series	Size	P(mm)	Po(mm)	P1(mm)	Bo(mm)	Ao(mm)	Ko(mm)	t(mm)
SWI	0603	4.0±0.1	4.0±0.1	2.0±0.05	1.88±0.05	1.30±0.05	1.10±0.05	0.20±0.02

8-3. Packaging Quantity

Chip size	0603
Reel	3000
Reel Size	7"x8mm

8-4. Tearing Off Force



The force for tearing off cover tape is 15 to 80 grams in the arrow direction under the following conditions.

Room Temp. (°C)	Room Humidity (%)	Room atm (hPa)	Tearing Speed mm/min
5-35	45-85	860-1060	300

Application Notice

- Storage Conditions(component level)
To maintain the solderability of terminal electrodes:
 1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
 2. Temperature and humidity conditions: Less than 40°C and 60% RH.
 3. Recommended products should be used within 12 months form the time of delivery.
 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

測試報告

Test Report

號碼(No.) : CE/2015/36745

日期(Date) : 2015/03/31

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西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD.

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以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as):

樣品名稱(Sample Description) : CERAMIC SERIES
樣品型號(Style/Item No.) : SWI SWC_I SERIES
收件日期(Sample Receiving Date) : 2015/03/24
測試期間(Testing Period) : 2015/03/24 TO 2015/03/31

測試結果(Test Results) : 請見下一頁 (Please refer to next pages).


Troy Chang / Manager - Tech
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory - Taipei

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測試結果(Test Results)

測試部位(PART NAME)No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321: 2008方法, 以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified (α -HBCDD, β -HBCDD, γ -HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.

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SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)



測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鄰苯二甲酸丁苯甲酯 / BBP (Butyl Benzyl phthalate) (CAS No.: 85-68-7)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di- (2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.
鄰苯二甲酸二異丁酯 / DIBP (Di-isobutyl phthalate) (CAS No.: 84-69-5)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di-isodecyl phthalate) (CAS No.: 26761-40-0; 68515-49-1)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.
鄰苯二甲酸二異壬酯 / DINP (Di-isononyl phthalate) (CAS No.: 28553-12-0; 68515-48-0)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n-octyl phthalate) (CAS No.: 117-84-0)	mg/kg	參考IEC 62321-8 (111/321/CD), 以氣相層析儀/質譜儀檢測之。 / With reference to IEC 62321-8 (111/321/CD). Analysis was performed by GC/MS.	50	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n.d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n.d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n.d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n.d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n.d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n.d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n.d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n.d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n.d.
十溴聯苯 / Decabromobiphenyl	mg/kg		5	n.d.
多溴聯苯醚總和 / Sum of PBDEs	mg/kg		-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg	5	n.d.	
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg	5	n.d.	

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鹵素 / Halogen				
鹵素(氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析。 / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	n.d.
鹵素(溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n.d.
鹵素(碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n.d.

備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試, 報告中的混合測試結果不代表其中個別單一材質的含量。(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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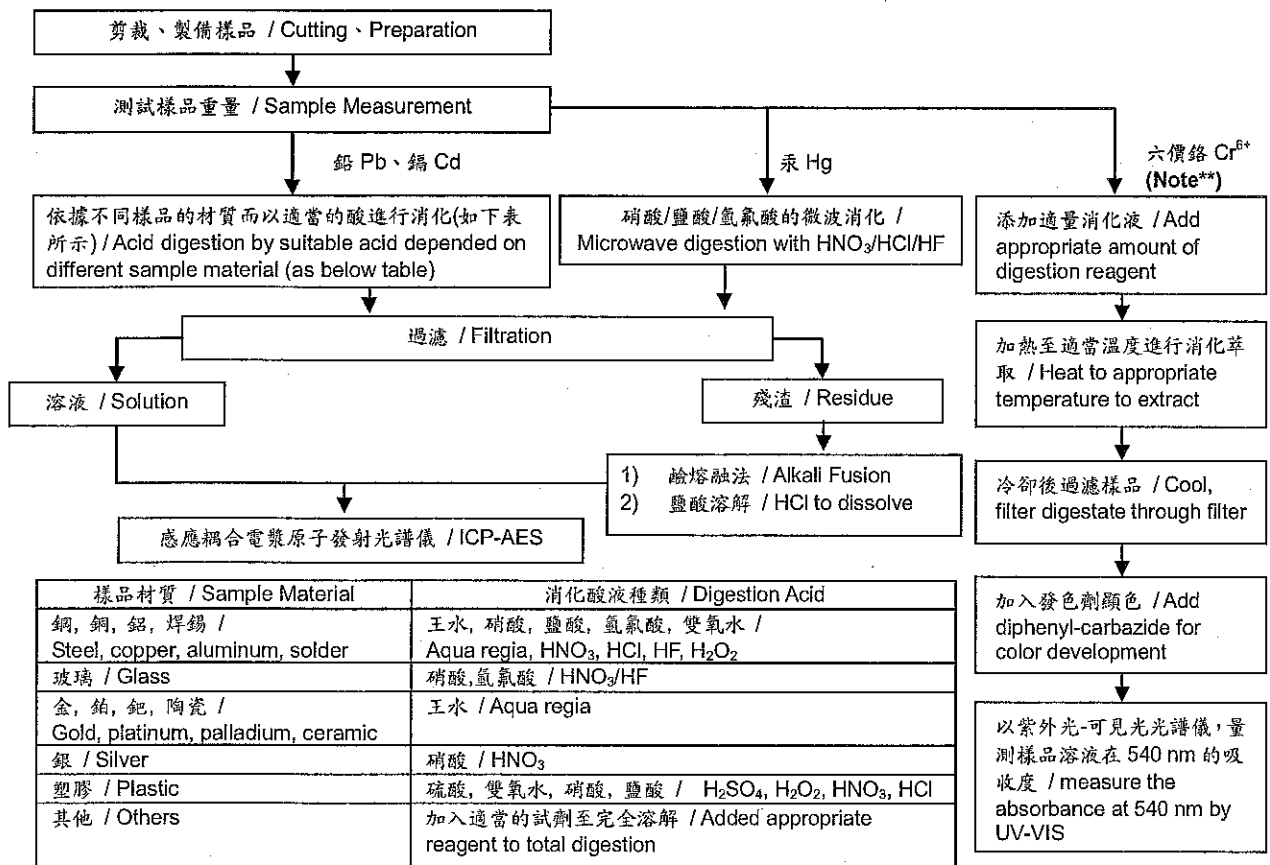
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- 1) 根據以下的流程圖之條件, 樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員: 楊登偉 / Name of the person who made measurement: Climgreat Yang
- 3) 測試負責人: 張啓興 / Name of the person in charge of measurement: Troy Chang



Note (For IEC 62321)**

- (1) 針對非金屬材料加入鹼性消化液, 加熱至 90~95°C 萃取。 / For non-metallic material, add alkaline digestion reagent and heat to 90~95°C.
- (2) 針對金屬材料加入純水, 加熱至沸騰萃取。 / For metallic material, add pure water and heat to boiling.

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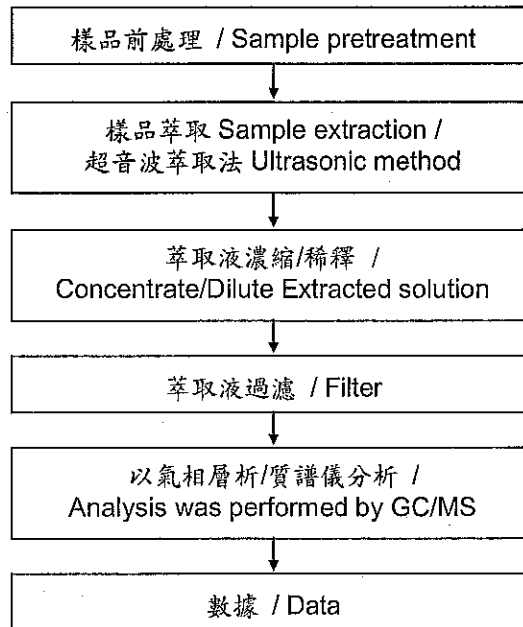
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六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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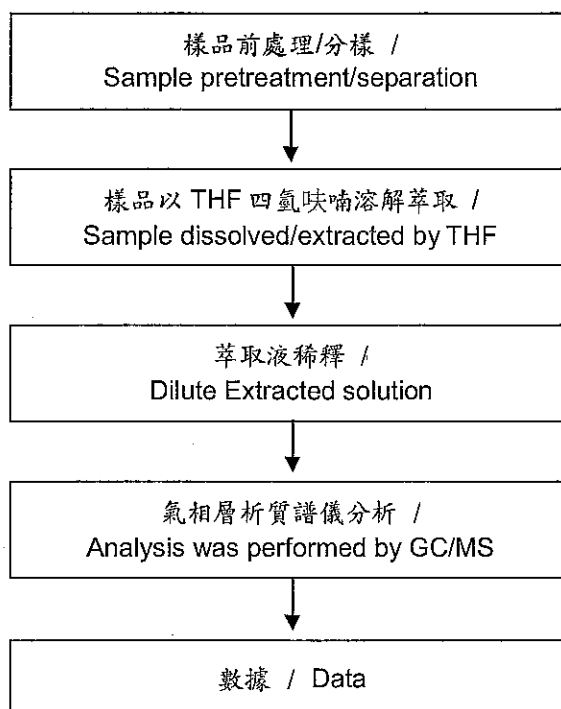
SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)



可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員：徐毓明 / Name of the person who made measurement: Andy Shu
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang

【測試方法/Test method: IEC 62321-8】



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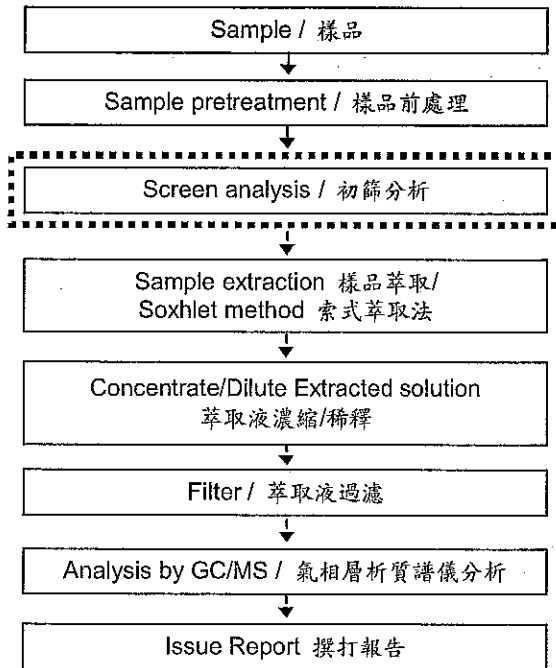
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多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang
- 初次測試程序 / First testing process —————>
- 選擇性篩檢程序 / Optional screen process>
- 確認程序 / Confirmation process - - ->



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測試報告

Test Report

號碼(No.) : CE/2015/36745

日期(Date) : 2015/03/31

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(臺慶精密電子(昆山)有限公司 / TAI-TECH ADVANCED ELECTRONICS (KUN-SHAN) CO. LTD.)

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(慶邦電子元器件(泗洪)有限公司 / TAIPAQ ELECTRONICS (SI-HONG) CO., LTD.)

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(江蘇省昆山市蓬朗鎮嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

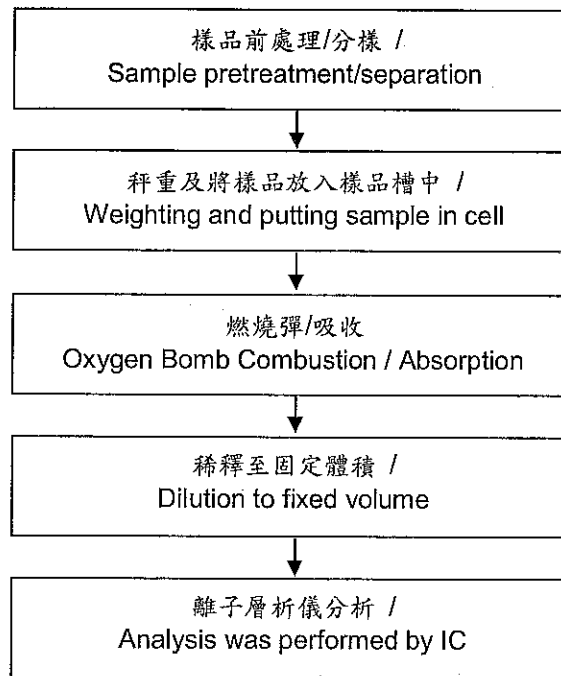
(桃園縣中壢市中壢工業區長春六路15號 / NO. 15, CHANGCHUN 6TH RD., JHONGLI CITY, TAOYUAN COUNTY 320, TAIWAN)

(江蘇省宿遷市泗洪縣經濟開發區金沙南路-高新技術產業園 / HIGH-TECH INDUSTRIAL DISTRICT, JINSHAJIANG ROAD, SIHONG COUNTY ECONOMIC, SUQIAN CITY, JIANGSU)



鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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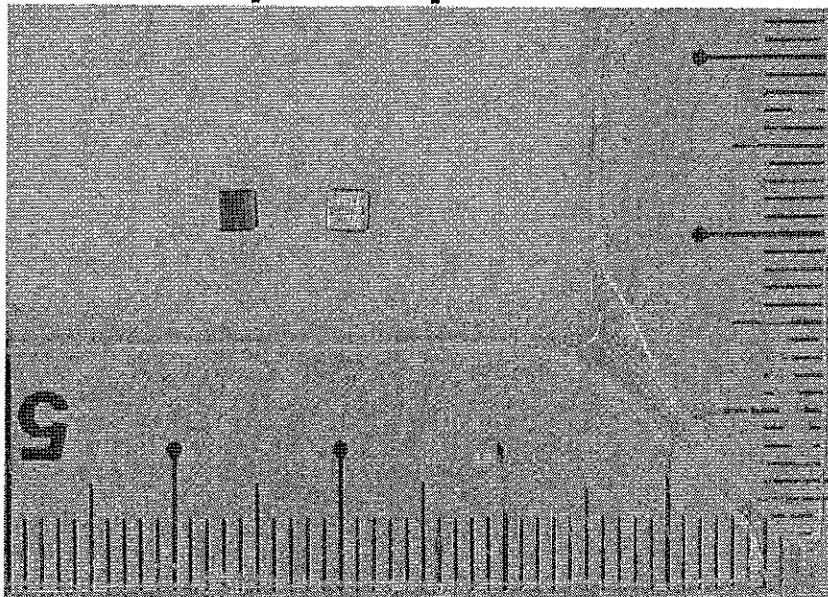
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* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。
(The tested sample / part is marked by an arrow if it's shown on the photo.)

CE/2015/36745



** 報告結尾 (End of Report) **

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